

09/844,675

L Number	Hits	Search Text	DB	Time stamp
1	1193710	integrated test core	USPAT	2004/03/21 14:47
2	970343	mixed-signal circuit\$1	USPAT	2004/03/21 14:47
3	515489	periodic waveform generator\$1	USPAT	2004/03/21 14:48
4	88334	generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)	USPAT	2004/03/21 14:49
5	463472	(integrated test core) and (mixed-signal circuit\$1)	USPAT	2004/03/21 14:50
6	167488	(periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1))	USPAT	2004/03/21 14:51
7	19366	(generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))	USPAT	2004/03/21 14:51
8	150658	waveform digitizer\$1	USPAT	2004/03/21 14:51
9	8885	extract\$3 and (arbitry waveform with (test circuit or CUT))	USPAT	2004/03/21 14:52
10	8885	(waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))	USPAT	2004/03/21 14:52
11	1025	((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1))))	USPAT	2004/03/21 14:53
12	1150264	compar\$4 and (reference signal\$! with analog response signal\$1)	USPAT	2004/03/21 14:56
13	965	((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1)))	USPAT	2004/03/21 14:57
14	1007560	digitiz\$3 with digital signal\$1	USPAT	2004/03/21 14:57
15	960	(((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)	USPAT	2004/03/21 14:58
16	444730	averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1)	USPAT	2004/03/21 15:00
17	540	(((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))	USPAT	2004/03/21 15:00
18	802149	generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1)	USPAT	2004/03/21 15:01
19	540	((((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))	USPAT	2004/03/21 15:02
20	2625848	integrated test core\$1programmable reference voltage generator\$1	USPAT	2004/03/21 15:03

21	540	(((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)	USPAT	2004/03/21 15:04
22	527130	reconstruction filter\$1	USPAT	2004/03/21 15:04
23	447	(((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)) and (reconstruction filter\$1)	USPAT	2004/03/21 15:04
24	73215	modulator\$1	USPAT	2004/03/21 15:04
25	134	((((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)) and (reconstruction filter\$1)) and (modulator\$1)	USPAT	2004/03/21 15:05
26	7388	714/? .ccls. or 324/? .ccls. or 375/? .cds. or 341/? .ccls. or 327/? .ccls. or 713/? .ccls.	USPAT	2004/03/21 15:06

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12	1150264	compar\$4 and (reference signal\$! with analog response signal\$1)	USPAT	2004/03/21 14:56
13	965	((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1)))	USPAT	2004/03/21 14:57
14	1007560	digitiz\$3 with digital signal\$1	USPAT	2004/03/21 14:57
15	960	((((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1))	USPAT	2004/03/21 14:58
16	444730	averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1)	USPAT	2004/03/21 15:00
17	540	((((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))	USPAT	2004/03/21 15:00
18	802149	generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1)	USPAT	2004/03/21 15:01
19	540	((((waveform digitizer\$1) and (extract\$3 and (arbitry waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))	USPAT	2004/03/21 15:02
20	2625848	integrated test core\$1programmable reference voltage generator\$1	USPAT	2004/03/21 15:03

21	540	(((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)	USPAT	2004/03/21 15:04
22	527130	reconstruction filter\$1	USPAT	2004/03/21 15:04
23	447	(((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)) and (reconstruction filter\$1)	USPAT	2004/03/21 15:04
24	73215	modulator\$1	USPAT	2004/03/21 15:04
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25	134	((((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)) and (reconstruction filter\$1)) and modulator\$1	USPAT	2004/03/21 15:17
32	706375	test\$3 and measur\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/21 15:11
33	79	((((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))))) and (compar\$4 and (reference signal\$! with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)) and (reconstruction filter\$1)) and modulator\$1) and (test\$3 and measur\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/21 15:12
34	11467281	circuit under test or device under test or built-in test or built-in self test or in-circuit test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/21 15:14

35	79	((((((((waveform digitizer\$1) and (extract\$3 and (arbitrary waveform with (test circuit or CUT)))) and ((generat\$3 and (arbitrary band-limited waveform\$1 near1 excitation)) and ((periodic waveform generator\$1) and ((integrated test core) and (mixed-signal circuit\$1)))) and (compar\$4 and (reference signal\$1 with analog response signal\$1))) and (digitiz\$3 with digital signal\$1)) and (averag\$3 and (periodic bit-stream signal\$1 with extract\$3 with DC reference voltage\$1))) and (generat\$3 and (signal\$1 with encod\$3 with DC voltage leve with periodic bit-stream signal\$1))) and (integrated test core\$1programmable reference voltage generator\$1)) and (reconstruction filter\$1)) and modulator\$1) and (test\$3 and measur\$3)) and (circuit under test or device under test or built-in test or built-in self test or in-circuit test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/21 15:14
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